Achieving accuracy in charge carrier mobility modelling in silicon
Mnatsakanov, T.T.; Gresserov, B.N.; Pomortseva, L.I. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 89-94: ill https://www.ester.ee/record=b1064031*est

CAD in the education of microelectronics at the Technical University of Budapest
Szekely, V.; Tarnay, K. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 146-151 https://www.ester.ee/record=b1064031*est

CAD of CCD VLSI
Zaycev, S.N.; Kanunnikov, A.I.; Pugachev, A.A.; Shilin, V.A. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 120-122: ill https://www.ester.ee/record=b1064031*est

Class-E inverter: SPICE simulation including parasitic elements
Liberatore, A.; Manetti, S.; Piccirilli, Maria Cristina; Reatti, A. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 69-75: ill https://www.ester.ee/record=b1064031*est

Complex simulation of punchthrough, tunneling and high-speed characteristics of scaled bipolar devices and circuits
Bubennikov, Alexander N.; Ishevsky, D.V. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 26-31: ill https://www.ester.ee/record=b1064031*est

Computation of MOS transistor channel currents using Gear methods in SPICE
Cremascoli, Paolo; Gubian, Paolo; Zanella, Marina Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 59-68: ill https://www.ester.ee/record=b1064031*est

Computational methods for semiconductor device simulation using adaptive composite grids
Boglaev, I.P.; Sirotkin, V.V. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 76-82: ill https://www.ester.ee/record=b1064031*est

Computer-aided analysis of the GTO thyristor current squeezing effect
Velmre, Enn; **Udal, Andres** Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 159-171: ill https://www.ester.ee/record=b1064031*est

Determination of transistor low freqency noise parameters for SPICE programme
Zeltinš, M.; Slaidinš, I. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 127-131: ill https://www.ester.ee/record=b1064031*est

The effective calculate scheme of the conjugate gradient method
Mulyarchick, S.G.; Belyavsky, S.S.; Popov, A.V. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 47-52: ill https://www.ester.ee/record=b1064031*est

Estonian electronic industry
Rang, Toomas Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 4-10: ill https://www.ester.ee/record=b1064031*est

Generalization of longitudinal-lateral scheme for two-dimensional transient semiconductor device simulation
Gunko, V.B.; Kucherenko, S.S.; Kudryashov, N.A.; Sytsko, Yu.I. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 107-112: ill https://www.ester.ee/record=b1064031*est

The investigation of distributed non-quasi-static high-current-density effects in advanced transistors
Bubennikov, Alexander; Kargashin, A. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 32-40: ill https://www.ester.ee/record=b1064031*est

ISTOC-2D: system of mixed device-circuit modeling for personal computer
Philatov, N.I.; Nakropin, B.O.; Yakovlev, D.G. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia,

October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 95-100: ill https://www.ester.ee/record=b1064031*est

Model reduction in VLSI circuit design
Rogoza, V.S. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 113-119: ill https://www.ester.ee/record=b1064031*est

Nonisothermal numerical simulation of semiconductor power devices
Velmre, Enn; **Udal, Andres** Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 139-145: ill https://www.ester.ee/record=b1064031*est

Numerical calculations of transient characteristics of a vertical field effect phototransistor taking into account resistance on the gate
Abashkina, S.; Rimshans, J.; Korolkov, V.I.; Tabarov, T. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 83-88: ill https://www.ester.ee/record=b1064031*est

Numerical scaling and speed-pover-optimization of polysilicon transistors & circuits
Bubennikov, Alexander Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 41-46: ill https://www.ester.ee/record=b1064031*est

Numerical simulation of photoelectric processes in semiconductor devices
Kucherenko, S.S.; Kudryashov, N.A. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 101-106: ill https://www.ester.ee/record=b1064031*est

A power fast reverse turn-on diode thyristor ТБР143
Graujnis, V.; Kovrov, A.; Kuzmin, V.; Hanstin, R.; Toomla, O. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 132-138: ill https://www.ester.ee/record=b1064031*est

The program for solving the scalar potential by using finite element method for IBM PC
Dmytryshyn, O.; Tchaban, V. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 53-58: ill https://www.ester.ee/record=b1064031*est

Simulation of charge transfer in CCDs for low temperature applications
Zaycev, S.N.; Zinis, K.A.; Chernokogin, V.V.; Shilin, V.A. Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 123-126 https://www.ester.ee/record=b1064031*est

Überblick der Situation in der Deutschen Elektronik- und Informatikindustrie
Rang, Toomas Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / S. 11-25: Ill https://www.ester.ee/record=b1064031*est

Обобщенные формулы для анализа лавинного умножения носителей заряда в pn-переходах
Velmre, Enn Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / c. 172-183: ил https://www.ester.ee/record=b1064031*est

Расчет и оптимизация параметров запираемых тиристоров с учетом внешней цепи
Куузик Э.И.; Кыверик К.Х.; Свирин А.В.; **Udal, Andres** Automation, simulation & measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / c. 184-199: ил https://www.ester.ee/record=b1064031*est